

## Test setup photos for HAC Test Report

|  |  |                         |   |
|--|--|-------------------------|---|
| Test report no.:                                 | SD_HAC_0849_07   | Date of report:         | 2008-12-12  |
| Template version:                                | 3.0  | Number of pages:        | 4   |
| Testing laboratory:                              | TCC Nokia San Diego Laboratory<br>12278 Scripps Summit Drive<br>SAN DIEGO CA. 92131<br>USA<br>Tel. +1 858 831 5000<br>Fax. +1 858 831 6500   | Client:                 | Nokia Corporation<br>12278 Scripps Summit Drive<br>SAN DIEGO CA. 92131<br>USA<br>Tel. +1 858 831 5000<br>Fax. +1 858 831 6500 |
| Responsible test engineer:                       | Julian Kim   | Product contact person: | Bill Griffin  |
| Measurements made by:                            | Julian Kim   |                         |   |
| Tested devices:                                  | RM-455 (Hearing aid mode active)   |                         |   |
| FCC ID:  | QMNRM-455  | IC:                     | 661X-RM455  |
| Supplement reports:                              | SD_HAC_0849_06, SD_HAC_0849_08   |                         |   |
| Testing has been carried out in accordance with: | <b>ANSI C63.19-2007</b><br>American National Standard for Methods of Measurement of Compatibility between Wireless Communications Devices and Hearing Aids   |                         |   |
| Documentation:                                   | The documentation of the testing performed on the tested devices is archived for 15 years at TCC Nokia.  |                         |   |
| Test results:                                    | <b>The tested device complies with the requirements in respect of all parameters subject to the test.</b> The test results and statements relate only to the items tested. The test report shall not be reproduced except in full, without written approval of the laboratory. |                         |   |

### Date and signatures:

For the contents:

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## 1. SUMMARY OF HAC RF EMISSION TEST REPORT

### 1.1 Test Details

|   |   |
|---|---|
| Period of test                              | 2008-12-04 to 2008-12-05                                  |
| SN, HW, SW and DUT numbers of tested device | SN: 004401/10/307247/2, HWID: 0310, SW: b14.05, DUT: 3107 |
| Batteries used in testing                   | BP-6MT, DUT: 3108, 3109                                   |
| State of sample                             | Prototype   |
| Notes                                       | AWF = -5 for GSM, 0 for WCDMA                             |

### 1.2 Picture of Device



Flip closed



Flip open

### 1.3 Test Positions

#### 1.3.1 Scan area centered at the acoustic output

The device was positioned such that Device Reference plane was touching the bottom of the Test Arch. The scan is centered at the acoustic output by aligning the acoustic output with the intersection of the Test Arch's middle bar and dielectric wire.



Photo of the device positioned under Test Arch